

JJF

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

JJF 1015-2014

**General Norm for Pattern Evaluation of Measuring Instruments
(English Translation)**

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Quarantine General Norm for Pattern Evaluation**

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Foreword

JJF 1015-2014 "General Norm for Pattern Evaluation of Measuring Instruments" is a guiding technical specification for pattern evaluation of measuring instruments.

JJF 1015-2014 "General Norm for Pattern Evaluation of Measuring Instruments" was modified on the basis of JJF 1015-2002 "General Norm for Pattern Evaluation and Pattern Approval of Measuring Instruments", which references to partial contents of No.19 "Pattern evaluation and pattern approval" of International Organization for Legal Metrology (OIML) and combines with the relevant requirements proposed by the metrological administrative department.

Compared with JJF 1015-2002, this Norm is only related to the pattern evaluation of the measuring instruments. The pattern approval shall be specified by relevant documents issued by the metrological administrative department. The main changes of this revision are as follows.

- Add terms "single product" and "series product" (see 3.3 and 3.4);
- Add "Application for Pattern Approval of Measuring Instruments that was accepted and entrusted by the government metrological administrative department" in the submitted technical information (see 4.1);
- Make significant change in the submitted test prototype (see 4.2);
- Improve the approved pattern or specify the basis-change of the previous

pattern evaluation (see 5.1);

- Refine the examination of technical information to make it more operatable (see 5.2);

- Divide the pattern evaluation into observation project and test project, so as easy for description (see 5.3 and 5.4);

- Add "function verification" (see 5.4.1);

- Refine "stability test" (see 5.4.7);

- Change the way of "determination of pattern evaluation result"; it shall be determined as qualified only when all the items for evaluation are qualified (see 5.5);

- Enrich the "pattern evaluation report" by requiring records and photos to be listed in the report as attachment (see 5.6);

- Change the handling of test prototype (see 6);

- Refine the "notices" of "pattern evaluation report" and specify 15-day appeal period (see Appendix A);

- Add tables of "measurement parameters for measuring instruments", "critical parts and materials", "list of equipment for pattern evaluation" and "list of evaluation items and evaluation results";

- Delete contents relating to pattern approval;

- Delete basic safety test;

- Delete tests for adaptability of measuring performance in transport simulation and retention simulation;

- Delete "handling for the first test failure".

The previous versions of this Norm are.

- JJF 1015-2002;

- JJF 1015-1990.

General Norm for Pattern Evaluation
of Measuring Instruments

1 Scope

This Norm is applicable to pattern evaluation of measuring instruments and approved pattern's compliance examination.

2 Normative references

This Norm takes the following documents as reference.

JJF 1016-2014 The Rules for Drafting Program of Pattern Evaluation of Measuring Instruments;

JJF 1051 Designation and Classification Code for Measuring Instruments;

JJF 1069 Rules for the Examination of the Service of Legal Metrological Verification.

For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

3 Terms and definitions

Terms and definitions defined by JJF 1001 "General Terms in Metrology and Their Definitions" AND the following terms and definitions are applicable to this Norm.

3.1 Measuring instrument

The single device or combination with one or multiple auxiliary equipment, which are used for measuring.

3.3 Single product

The product of one specification or model.

3.4 Series product

A group of products with same measuring principle, same or similar structure (appearance), which meet one of the following conditions.

4 Technical information and test prototype that shall

be submitted by the application organization

The applicant shall provide the technical information and test prototype required by pattern evaluation to the technical agency who undertakes the pattern evaluation.

4.1 Technical information

The following technical information shall be provided in two-sets by the applicant.

4.2 Test prototype

The technical agency who undertakes the pattern evaluation shall require the applicant to provide the test prototype according to provisions of pattern evaluation outline if there is any; otherwise, determine the specification and quantity of the prototype according to provisions of 6.13 of JJF 1016-2014.

5.1 General principles

The pattern evaluation shall be carried out according to the pattern evaluation outline.

5.2.1 Comparing with 4.1 of this Norm, review if the technical information is complete.

5.2.2 Review if the units of measurement, the external structure, marks, anti-spoofing measures, etc. are in line with the legal management requirements.

Meanwhile, review if the names of measuring instruments comply with provisions of JJF 1051 and the "Catalogue of Measuring Instruments under the Legal Administration of the People's Republic of China (Pattern Approval)."

5.3 Observation item evaluation

Evaluate the items requiring no test in legal management requirements, metering requirements and common technical requirements proposed by the